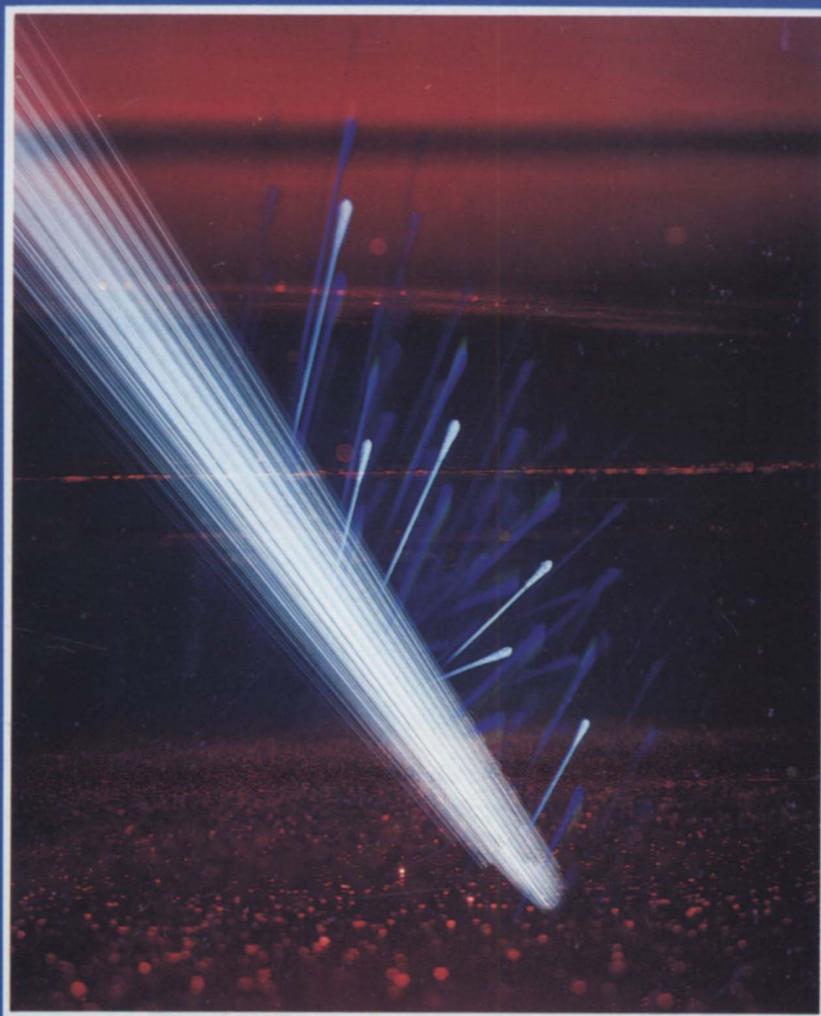


MRS BULLETIN

Materials Research Society Vol. X No. 6 November/December 1985

1985 MRS FALL MEETING



Also:

1986 MRS Officers and Councillors Selected
John W. Cahn Receives Von Hippel Award
MRS Short Course Program Expands

RBS SURFACE ANALYZER LOOK INTO IT!

METALS

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ON THE COVER *Rutherford Backscattering Spectrometry (RBS).*

A collimated helium ion beam is envisioned penetrating through diverse multi-layered material at glancing incidence. Elastic collisions with sample nuclei occur, resulting in well-defined Rutherford backscattering. Photo courtesy of General Ionex Corporation, Newburyport, MA.

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